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Complete if Known

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Filing Date:	December 8, 2006
First Named Inventor:	Nigel P. Smith
Art Unit:	2823
Examiner Name:	William D. Coleman
Attorney Docket No.:	NAN154 US 8026

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Examiner Signature:	/W. David Coleman/	Date Considered:	05/23/2008
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* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.